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	Application Number	not yet assigned	926
INFORMATION DISCLOSURE	Filing Date	July 20, 2001	906/
STATEMENT BY APPLICANT	Applicant(s)	Jean-Luc Leveque	
	Group Art Unit	To Be Determined	• ===
(use as many sheets as necessary)	Examiner Name	To Be Determined	

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EXAMINER	OTHER DOCUMENTS						
INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.						
	French Search Report dated May 7, 2001 and references which are cited herein						

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